

<b>Notice of References Cited</b>	Application/Control No. 10/814,381	Applicant(s)/Patent Under Reexamination LEE ET AL.	
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#### U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-2003/0205477 A1	11-2003	Chou et al.	204/230.7
	B	US-2002/0079230 A1	06-2002	Basol et al.	204/252
	C	US-6,802,946 B2	10-2004	Basol et al.	204/242
	D	US-6,565,729 B2	05-2003	Chen et al.	204/DIG.7
	E	US-6,425,991 B1	07-2002	Tran et al.	204/230.7
	F	US-6,261,433 B1	07-2001	Landau, Uziel	204/230.7
	G	US-6,217,734 B1	04-2001	Uzoh, Cyprian E.	204/289
	H	US-4,977,330 A	12-1990	Batchelder et al.	250/559.27
	I	US-4,695,479 A	09-1987	Nakakura et al.	438/703
	J	US-4,358,338 A	11-1982	Downey et al.	204/192.33
	K	US-			
	L	US-			
	M	US-			

#### FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

#### NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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	X	

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